

Soft matter at and beyond the limits of soft x-ray microscopy

Rainer H. Fink

(Friedrich-Alexander-University of Erlangen, Nürnberg, Germany)

Lundi 26 mars 2018 – 14h00
Amphithéâtre SOLEIL

Zone-plate based soft x-ray microspectroscopy has developed into a routine technique to analysing all kind of materials. Specifically the investigation of molecule-based materials gains from the chemical fingerprint sensitivity of near-edge x-ray absorption fine structure. We will discuss various applications of the SLS PoLux-STXM to soft matter specimens, ranging from polymer materials, polymer blends, organic nanocrystals and in-operando studies of organic electronic thin film devices. Since spatial resolution in state-of-the-art zone plate-based microscopy is limited, complementary techniques are required that offer chemical insight also beyond the present STXM resolution level. Therefore, soft x-ray resonant scattering has been employed to resolve structures in the sub-10 nm regime.



Ce séminaire sera suivi d'une pause café

SEMINAIRE

Formalités d'entrée : accès libre dans l'amphi du pavillon d'Accueil.

Si la manifestation a lieu dans le Grand Amphi SOLEIL du Bâtiment Central merci de vous munir d'une pièce d'identité (à échanger à l'accueil contre un badge d'accès)

SYNCHROTRON SOLEIL

L'Orme des merisiers - Saint-Aubin - BP48 - 91192 GIF S/YVETTE cedex

www.synchrotron-soleil.fr/fr/evenements

CONTACT : sandrine.vasseur@synchrotron-soleil.fr